# Search Notes



#### Applicant(s)/Patent Under Application/Control No.

10603055

Reexamination BLASI ET AL.

Art Unit

Examiner Jacob, Mary C

2123

# SEARCHED

Class	Subclass	Date	Examiner
703	15	2/21/08	MCJ

### SEARCH NOTES

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Search Notes	Date	Examiner	
Updated Inventor Name Search: EAST	2/21/08	MCJ	
Updated Assignee Name Search: EAST	2/21/08	MCJ	
Updated East Search: See search History	2/21/08	MCJ	
Google Scholar: catalog, memory model, test bench generator; "memory model", test bench generator, ports, synchronous, asynchronous, catalog or database or repository	2/21/08	MCJ	
IEEE: test bench generator, memory models, catalog or repository or database; catalog or repository or database near4 memory models; test bench generation and memory models	2/21/08	MCJ	

#### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
	PG Pub Text Search: see search history printout	2/21/08	MCJ

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